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Notice of Allowability	Application No.	Applicant(s)	
	10/711,153	YING, CHANGSHENG	
	Examiner	Art Unit	
	Suchin Parihar	2825	
The MAILING DATE of this communication app All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85 NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT of the Office or upon petition by the applicant. See 37 CFR 1.37	S (OR REMAINS) CLOSED in to 5) or other appropriate commun RIGHTS. This application is suld and MPEP 1308.	nis application. If not included cation will be mailed in due course. THIS	V€
2. ☑ The allowed claim(s) is/are <u>1-10,15 and 16</u> .			
a) ☐ Acknowledgment is made of a claim for foreign priority a) ☐ All b) ☐ Some* c) ☐ None of the: 1. ☐ Certified copies of the priority documents have 2. ☐ Certified copies of the priority documents have 3. ☐ Copies of the certified copies of the priority documents have 3. ☐ Copies of the certified copies of the priority of International Bureau (PCT Rule 17.2(a)). * Certified copies not received: Applicant has THREE MONTHS FROM THE "MAILING DATE noted below. Failure to timely comply will result in ABANDON THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 4. ☐ A SUBSTITUTE OATH OR DECLARATION must be sub INFORMAL PATENT APPLICATION (PTO-152) which gifted including changes required by the Notice of Draftspector of the Paper No./Mail Date [a) ☐ including changes required by the attached Examine Paper No./Mail Date [b) ☐ including changes required by the attached Examine Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR each sheet. Replacement sheet(s) should be labeled as such in the department of the paper No./Mail Date	ve been received. ve been received in Application documents have been received in Application documents have been received in Application. E" of this communication to file and MENT of this application. Emitted. Note the attached EXAM invest reason(s) why the oath or document be submitted. Example of the submitted of the example of the header according to 37 CFR cosit of BIOLOGICAL MATER.	No In this national stage application from the reply complying with the requirements INER'S AMENDMENT or NOTICE OF eclaration is deficient. PTO-948) attached In the Office action of drawings in the front (not the back) of 1.121(d). RIAL must be submitted. Note the	
Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☐ Information Disclosure Statements (PTO/SB/08), Paper No./Mail Date 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. Interview Sun Paper No./M 7. Examiner's A	rmal Patent Application nmary (PTO-413), ail Date <u>same as OA</u> mendment/Comment satement of Reasons for Allowance	
	S	SUPERVISORY PATENT EXAMINER	

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DETAILED ACTION

EXAMINER'S AMENDMENT

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Steve Y. Cho (Reg.# 44,612) on Monday 5/29/2007.

2. The application has been amended as follows:

In the Claims

Cancel claim 14.

(Amendment was made in order to place this application into a condition for allowance)

Reasons For Allowance

3. The following is an examiner's statement of reasons for allowance:

Claims 1-10 and 15-16 are allowed because the prior art made of record does not teach or suggest a method for checking optical proximity correction data in the manner as recited in the claims.

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- 4. With respect to claims 1-10, the prior art fails to teach the combination of steps in claim 1 including the following particular steps as recited in claim 1:
 - (a) dividing a chip region into at least first and second regions;
 - (b) selecting the first region from the divided regions;
- (j) repeating the steps (a) to (i) to generate a defect report at least on the first and second regions;
 - (k) analyzing the defect report to identify one or more problematic patterns; and
 - (I) identifying unique patterns from one or more problematic patterns.
- 5. With respect to claims 15-16, the prior art fails to teach the combination of steps in claim 15 including the following particular steps as recited in claim 15:

flagging the first structure in the first database if the first critical dimension is less than the first drawn dimension in the first database to generate a defect report; analyzing the defect report to identify one or more problematic patterns; and

identifying unique patterns from one or more problematic patterns.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Suchin Parihar whose telephone number is 571-272-6210. The examiner can normally be reached on Mon-Fri, 8:30am-5:00pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Jack Chiang can be reached on 571-272-7483. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300. Information regarding the status of an application may be obtained from the Patent

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Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Suchin Parihar Examiner AU 2825

SUPERVISORY PATENT EXAMINER